

CsI(TI) Arrays

CsI(TI) arrays have been widely used in X-ray security inspection systems, we design and develop the pixelated CsI(TI) crystal in reflection coating, the TiO2 is used as the reflector/separator between each single element, the configuration can be linear, 2D array or other special design, with high resolution and high sensitive properties to achieve excellent imaging quality.



Features

- High light output
- Emission wavelength at 550 nm
- Compatible with photodiode readout

Application Notes

- X-ray security inspection
- High energy physics
- Container inspection





Modules or types

Single element size: customized Linear array: 8, 16, 32, 64...elements 2-Dimensional array: 6×10, 12×18, 24×36, ect. Light output: 55,000 Photons/Mev Afterglow: 0.6%(max) after 100ms Reflector: polymer with TiO₂(excellent reflection to ensure minimized cross talk) Reflector thickness: Customized

Structure diagrams





Basic Properties

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Density(g/cm2)	4.51
Melting Point (K)	894
Cleavage plane	None
Hardness(Mohs)	2
Hygroscopic	Slightly
Refractive index at emission peak	1.79
Emission Peak wavelength (nm)	550
Lower wavelength cutoff (nm)	320
Decay time (ns)	1000
Light yield (photons/KeV)	54



Csl, Csl(Na) and Csl(Tl)